



Figure 1: B — MESFET element.

REEDATM Form: mesfetm:<instance name> n_1 n_2 n_3 <parameter list>

n_1 is the drain node

n_2 is the gate node

n_3 is the source node

parameter list see table 1 for parameter list

n_1 is the drain node

n_2 is the gate node

n_3 is the source node

ModelName is the model name

Area is the optional relative area factor. (Units: none; Default: 1; Symbol:Area)

Example:

In *REEDATM*:

mesfetm:b1 2 0 3

In SPICE:

B1 3 7 4 GAAS12 0.5

II The Materka-Kacprzac Model

Model Parameters:

Name	Description	Units	Default
AFAB	Slope factor of breakdown current ($AFAB$)	1/V	0.0
AFAG	Slope factor of gate conduction current ($AFAG$)	1/V	38.696
AREA	Area Multiplier ($AREA$)	-	1.0
C10	Gate source Schottky barrier capacitance for (C_{10})	F	0.0
CF0	Gate drain feedback capacitance for (C_{F0})	F	0.0
CLS	Constant parasitic component of gate-source capacitance (C_{LS})	F	0.0
E	Constant part of power law parameter (E)	-	2.0
GAMA	Voltage slope parameter of pinch-off voltage (γ)	1/V	0.0
IDSS	Drain saturation current for (I_{DSS})	A	0.1
IG0	Saturation current of gate-source Schottky barrier (I_{G0})	A	0.0
K1	Slope parameter of gate-source capacitance (K_1)	1/V	1.25
KE	Dependence of power law on V_{GS} , (K_E)	1/V	0.0
KF	Slope parameter of gate-drain feedback capacitance (K_F)	1/V	1.25
KG	Drain dependence on V_{GS} in the linear region, (K_G)	1/V	0.0
KR	Slope factor of intrinsic channel resistance (K_R)	1/V	0.0
RI	Intrinsic channel resistance for (R_I)	Ω	0.0
SL	Slope of the drain characteristic in the saturated region, (S_L)	S	0.15
SS	Slope of the drain characteristic in the saturated region (S_S)	S	0.0
T	Channel transit-time delay (τ)	s	0.0
VBC	Breakdown voltage (V_{BC})	V	10^{10}
VPO	Pinch-off voltage for (V_{P0})	V	-2.0

The physical constants used in the model evaluation are

k	Boltzman's constant	$1.3806226 \cdot 10^{-23}$ J/K
q	electronic charge	$1.6021918 \cdot 10^{-19}$ C

Standard Calculations

$$V_{TH} = (kT)/q \quad (1)$$

T is the analysis temperature

V_{DS} Intrinsic drain source voltage
 V_{GS} Intrinsic gate source voltage
 V_{GD} Intrinsic gate drain voltage

Device Equations:

Current Characteristics

$$I_{DS} = Area I_{DSS} \left[1 + S_S \frac{V_{DS}}{I_{DSS}} \right] \left[1 - \frac{V_{GS}(t - \tau)}{V_{P0} + \gamma V_{DS}} \right]^{(E + K_E V_{GS}(t - \tau))} \times \tanh \left[\frac{S_L V_{DS}}{I_{DSS}(1 - K_G V_{GS}(t - \tau))} \right] \quad (2)$$

$$I_{GS} = Area I_{G0} \left[e^{AFAG V_{GS}} - 1 \right] - I_{B0} \left[e^{-AFAB(V_{GS} + V_{BC})} \right] \quad (3)$$

$$I_{GD} = Area I_{G0} \left[e^{AFAG V_{GD}} - 1 \right] - I_{B0} \left[e^{-AFAB(V_{GD} + V_{BC})} \right] \quad (4)$$

$$R_I = \begin{cases} R_{10}(1 - K_R V_{GS})/Area & K_R V_{GS} < 1.0 \\ 0 & K_R V_{GS} \geq 1.0 \end{cases} \quad (5)$$

Capacitance

$C_{LVL} = 1$ (default) for the standard Materka-Kacprzak capacitance model described below is used. The Materka-Kacprzak capacitances are

$$C'_{DS} = C_{DS} \quad (6)$$

$$C'_{GS} = \begin{cases} [C_{10}(1 - K_1 V_{GS})^{M_{GS}} + C_{1S}] & K_1 V_{GS} < F_{CC} \\ [C_{10}(1 - F_{CC})^{M_{GS}} + C_{1S}] & K_1 V_{GS} \geq F_{CC} \end{cases} \quad (7)$$

$$C'_{GD} = \begin{cases} Area [C_{F0}(1 - K_1 V_1)^{M_{GD}}] & K_1 V_1 < F_{CC} \\ Area [C_{F0}(1 - F_{CC})^{M_{GD}}] & K_1 V_1 \geq F_{CC} \end{cases} \quad (8)$$

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Credits:

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